



# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

**Datacolor Technology Suzhou**  
**288 Shengpu Road**  
**Suzhou Jiangsu, China 215021**

Fulfills the requirements of

**ISO/IEC 17025:2017**

In the field of

**CALIBRATION**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

A handwritten signature in black ink, appearing to read 'R. Douglas Leonard Jr.', is positioned above a horizontal line.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 20 February 2023

Certificate Number: AC-1759



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

**Datacolor Technology (Suzhou) Co., Ltd**

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**CALIBRATION**

Valid to: **February 20, 2023**

Certificate Number: **AC-1759**


**Photometry and Radiometry**

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
8°:t Geometry – Spectral Reflectance Factor	(70 to 100) %R (380 to 390 nm) (400 to 750 nm)	0.44 %R 0.38 %R	CERAM Ceramic White tile, M2009 Spectrometer, JJG 453-2002
8°:d Geometry - Spectral Reflectance Factor	(70 to 100) %R (380 to 390 nm) (400 to 750 nm)	0.43 %R 0.37 %R	CERAM Ceramic White tile, M2009 Spectrometer, JJG 453-2002
d:0° Geometry - Spectral Reflectance Factor	(70 to 100) %R (380 to 700 nm)	0.67 %R	CERAM Ceramic White tile, DC245 Spectrometer, JJG 453-2002
Absolute 0°:45°- Bidirectional Spectral Reflectance Factor	(70 to 100) %R (400 to 410 nm) (420 to 700 nm)	0.87 %R 0.79 %R	CERAM Ceramic White tile, Elrepho Spectrometer, JJG 453-2002

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. The uncertainty term R represents Spectral Reflectance.
2. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1759.



R. Douglas Leonard Jr., VP, PILR SBU